Dual Slope Direct Digital Converter for Bridge Connected Resistive Sensors

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Abstract—A dual slope direct digital converter (DSDDC) suitable for resistive sensor elements already connected in a bridge form is presented. A conventional dual slope analog to digital converter (DS-ADC) is altered with an intentionally introduced instrumentation amplifier (INA) to realize the proposed DDC. The DSDDC accepts bridge connected resistive sensor elements as input and provides a digital output that is proportional to the quantity being sensed by the sensor elements. The results obtained from simulation of the proposed DSDDC indicate a worst case error in the output to be < ±0.03 %. Experimental results from a prototype unit, presented herein, demonstrate the practicality the scheme. Worst case error of the prototype unit was found to be < ±0.07 % with test conducted using standard decade resistance boxes emulating the sensor elements. The worst case error in the prototype was < ±0.05 % when tested with a load-cell made of four strain gauges.

Keywords- Direct digital converter; Resistive sensors; Strain gauges; Wheatstone bridge; Instrumentation amplifier; Dual slope digital converter;

I. INTRODUCTION

Resistive sensing elements are popular for sensing several physical parameters such as displacement (linear and angular), strain, force, pressure, temperature and torque [1] - [5]. The performance of such resistive sensor elements is affected by environmental factors. For example, variation in the operating temperature of a resistive strain gage introduces an error in its strain sensing characteristics [6]. It is possible to eliminate the temperature effect with either two (half-bridge) or four active sensor elements (full-bridge) connected to form a Wheatstone bridge circuit [4] - [6]. Use of two or four active resistive sensor elements in a bridge form, apart from providing temperature compensation, provides increased sensitivity and linearity at the output. Sensors are interfaced to a digital instrumentation system to exploit the processing power and better user interface available with digital instrumentation systems. To interface resistive type sensor(s) to a digital instrumentation system, first an analog signal conditioning circuit is employed to convert the variation in the resistance(s) of the sensor element(s) into an analog voltage. The analog voltage is then converted to digital utilizing an analog to digital converter (ADC). It would be advantageous if we can interface the resistive elements directly to a suitable 'resistance to digital converter', dispensing with the analog signal conditioning circuit [7]. Such a direct digital converter (DDC) will possess advantages such as reduced complexity, reduced power and increased reliability. Due to this fact, schemes that convert the variation in the resistances of sensor elements into quasi-digital forms like frequency and time period have been

proposed [8], [9]. However, such schemes require additional interface to convert the quasi-digital outputs into digital. It is reported that such methods suffer due to change in temperature and aging [10] – [12]. Direct Digital Converters (DDC), where the sensor elements are directly operated by an analog-to-digital converter, eliminating the intermediate analog signal conditioning circuit, have been proposed [7], [13] - [15]. The DDC reported earlier for two or four resistive sensors in bridge form requires three integration periods for conversion [15].

We now present a dual slope type direct digital converter that accepts resistive sensor elements in a bridge circuit form and provides a digital output proportional to the physical quantity being sensed by the resistive sensor elements. Compared to the scheme reported earlier [15] that requires three integrations for a conversion, the present scheme requires only two integration periods and hence will be 33 % faster than the previous scheme. The proposed scheme easily handles resistive sensor elements with low sensitivity.

II. PROPOSED DUAL SLOPE DIRECT DIGITAL CONVERTER

The block schematic of the proposed dual slope direct digital converter is shown in Fig. 1. The sensor elements R_1, R_2, R_3 and R_4, are connected in a Wheatstone bridge form. As in any bridge form of sensor elements, here too, the elements are arranged such that resistances of elements R_2 and R_3 increase with the physical quantity, say x, being sensed. On the other hand, resistances of elements R_1 and R_4 decrease with increasing x. In such a case the resistances of these sensing elements can be expressed as:

$$R_1 = R_4 = R_o(1 \mp kx) \qquad (1)$$

$$R_2 = R_3 = R_o(1 \pm kx) \qquad (2)$$

In (1) and (2), k represents the transformation constant of the sensor elements and R_0 indicates the nominal value of the sensor element when x, the physical quantity being sensed by it, is zero.

As in a conventional dual slope ADC, the proposed DSDDC also contains a control and logic unit (CLU) with an integral timer-counter, an integrator (opamp OA_4 with capacitor C_I in its feedback and input resistor R_I), and a comparator as indicated in Fig. 1. The output voltage of integrator, v_{oi}, is fed as input to comparator OC which is configured as a zero crossing detector. The comparator output will be high if v_{oi} is positive and it will be low if v_{oi} is negative. A high to low or low to high transition indicates zero crossing. It is easily seen in Fig. 1 that node p of the sensor bridge is connected to the
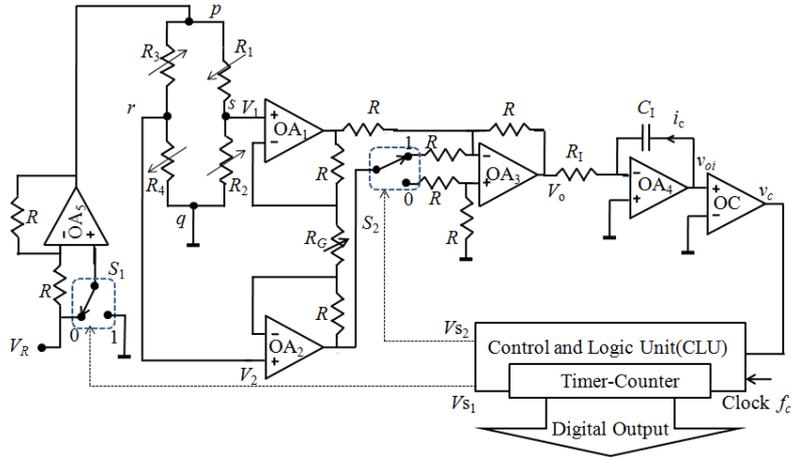
Fig. 1. Block schematic of the proposed DDC for bridge connected resistive sensors

output of opamp OA_5, which provides the necessary excitation to the bridge. The node q of the bridge is connected to ground and the nodes s and r are connected to the inputs of opamps OA_1 and OA_2. Opamps OA_1, OA_2 and OA_3 constitute a modified instrumentation amplifier, INA. The SPDT switch S_2 configures opamp of OA_3 to be a differential (S_2 in position 0) or summing amplifier (S_2 at position 1).

The CLU senses the output of comparator v_C, generates necessary switching signals and achieves required sequence of operations required to implement the logic of the proposed DSDDC. A typical conversion cycle of the DSDDC is made of two distinct phases of operation, namely, an auto-zero phase and a conversion phase. An auto-zero phase precedes a typical conversion phase so as to ensure that the output of the integrator is made zero, a condition essential for proper operation of the dual slope principle. For continuous conversion (a new conversion succeeding a previous one, endlessly), the auto-zero phase is needed only once at the start, since at the end of a conversion, the integrator's output will be zero and hence a new conversion can start without an auto-zero phase.

A. Auto zero phase

In the auto-zero phase, the CLU senses v_C. If v_C is high (v_{oi} is positive) the CLU sets the switches S_1 and S_2 to position '1'. In this situation OA_5 will act as an inverting amplifier providing a voltage of $-V_R$ to node p and OA_3 will act as an inverting summing amplifier and its output V_o will be $-(V_1+V_2)$, where

$$V_1 = \frac{V_p(1 \pm kx)}{2} \quad \text{and} \tag{3}$$

$$V_2 = \frac{V_p(1 \mp kx)}{2} \quad . \tag{4}$$

V_p is the voltage at node p. $V_p = V_R$ when S_1 is in position '0' and $V_p = -V_R$ when S_1 is shifted to position '1'. For the condition S_1 and S_2 in position '1', a current $i_c = -V_R/R_I$ will flow and discharge the capacitor C_I. Thus, the integrator output

will start decreasing and reach zero as shown in Fig. 2 by the dashed line shown during the auto-zero phase.

On the other hand if v_C is low (indicating a negative v_{oi}) the CLU will set switch S_1 to position '0' and S_2 to position '1'. In this case OA_5 will act as a buffer giving $+V_R$ to node p and OA_3 will again act as a summing amplifier and its output will be sum of V_1 and V_2. Now current $i_c = V_R/R_I$ will flow. Once again the charge in the capacitor C_I will be removed resulting in the integrator output rising to zero from the negative initial condition.

In either case, when the integrator output reaches zero, output of the comparator will flip ('1' to '0' in the first case and '0' to '1' in the second case) signaling the end of auto-zero phase to the CLU. The CLU sensing the flip in v_C starts a conversion phase.

B. Conversion phase

The conversion phase, as in any dual slope converter, has a pre-set integration period T_1 and a measured de-integration period T_o. At the start of a conversion phase, the CLU sets switches S_1 and S_2 in position '0' and initiates the first integration period T_1. The CLU starts the internal timer
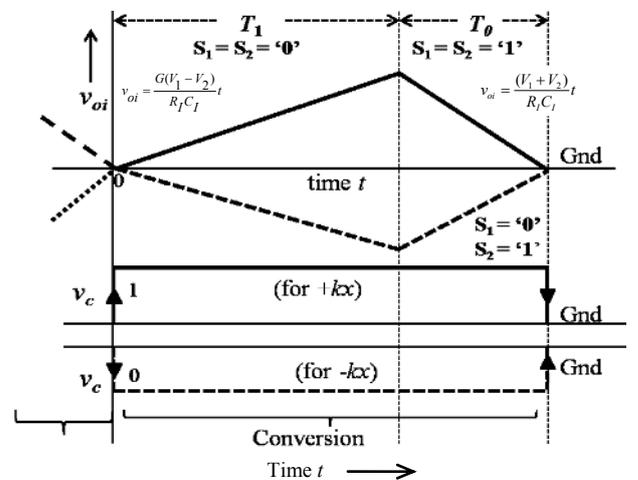

Fig. 2. Waveforms at cardinal points of the proposed DDC

simultaneously and maintains the switch positions for the first integration period for a certain count, say N_1 ($T_1 = N_1 T_c$, where T_c is the period of the clock fed to the timer-counter of the CLU). For this case, the output V_o of opamp OA_3 is:

$$V_o = -G(V_1 - V_2) , \qquad (5)$$

where $G = [1 + 2(R/R_G)]$. If the physical quantity being sensed, x, is positive then $R_2 > R_1$ and hence the current $i_c = V_o/R_I$ will flow into the capacitor C_I of the integrator and the integrator output v_{oi} will ramp up (indicated as solid line in Fig. 2) with time as:

$$v_{oi} = \frac{G(V_1 - V_2)}{R_I C_I} t = V_R G k x\, t \qquad (6)$$

At the end of T_1, the CLU is programmed to sense the comparator output v_C. Since $v_C = $ '1' (for positive x) the CLU logic changes the position of switches S_1 and S_2 to position '1' and restarts the timer counter. For this condition the output V_o of opamp OA_3 will be $V_o = -(V_1 + V_2) = V_R$. The current through C_I will now be $i_c = -V_R/R_I$. This current will discharge the capacitor C_I, forcing the output voltage of the integrator to decrease with time and reach zero. As soon as the output of the integrator reaches zero, the output of the comparator will change state signaling to the CLU that the conversion phase is over. The count value at this point, say N_o, from the timer-counter is read by the CLU and displayed as the final output.

If x is negative ($R_2 < R_1$) then during the first integration period T_1, the integrator output will increase in the negative direction and at the end of T_I will be $-V_R G k x\, T_1$. Hence at the end of T_1, the output v_C of the comparator will be '0'. Sensing v_C to be '0' the CLU sets switch S_1 in position '0' and S_2 in position '1' and restarts the timer-counter. The voltage on node p will now be $+V_R$ and $V_o = -(V_1 + V_2) = -V_R$. Thus a current $i_c = V_R/R_I$ will flow into C_I , discharging it. For this case, the integrator output will ramp up and reach zero as indicated by the dashed line (during conversion phase) in Fig. 2. Once again the comparator output will flip (from '0' to '1') as soon as the integrator output reaches zero. Sensing the flip, the CLU stops the timer-counter, reads the value of the timer-counter and displays it as the output.

In either case (x is positive or negative), the charge acquired by the capacitor C_I during T_1 must be equal to the charge removed from C_I during T_o since the net charge in C_I at the end of T_o is zero. The charge balance results in:

$$\frac{G(V_1 - V_2)}{R_I C_I} T_1 = \frac{(V_1 + V_2)}{R_I C_I} T_o \qquad (7)$$

Substituting the values V_1 and V_2 from (3) and (4) into (7) we get :

$$G V_R k x T_1 = V_R T_o \qquad (8)$$

By rearranging (8), x is derived as:

$$x = \frac{1}{kGT_1} T_o. \qquad (9)$$

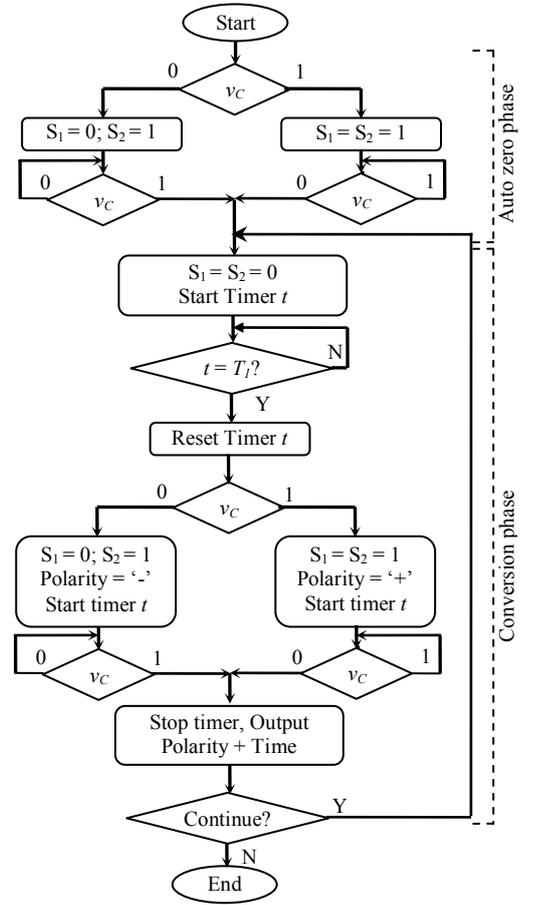Since $T_1 = N_1 T_C$ and $T_o = N_o T_C$, (9) can be simplified as:

Fig. 3. Flowchart showing the conversion logic of the DDC

$$x = \frac{1}{kGN_1} N_o. \qquad (10)$$

The polarity of x can be easily determined by sensing the output v_C) of comparator at the end of period T_1. The sequence of operations of the DSDDC is clearly depicted in the flowchart shown in Fig. 3.

III. SIMULATION STUDIES

The functionality of the DSDDC presented here was first checked by simulating the circuit using circuit simulation tool, LTSpice. The opamps used in the simulation are selected to match the performance and characteristics of practical opamps, later used to build the prototype DSDDC. The control logic is simulated by using four switches controlled by pulse waveforms and logic gates. The nominal values (R_o) of four resistors were set as 1.0 kΩ and resistances were varied in steps of 10 Ω in the range 900 Ω to 1100 Ω ($kx = \pm 10$ % of R_o). The output obtained from simulation was plotted and a best fit also obtained for that which is clearly indicated in Fig. 4. The worst case error obtained after employing best fit using linear regression analysis is found to be $< \pm 0.03$%.

IV. EXPERIMENTAL RESULTS

In order to verify the practicality of the proposed DSDDC, a prototype unit was built and tested. The reference voltage V_R was obtained using reference voltage generator IC LM385. All the opamps in the circuit of Fig. 1 are of type: IC OP07. The
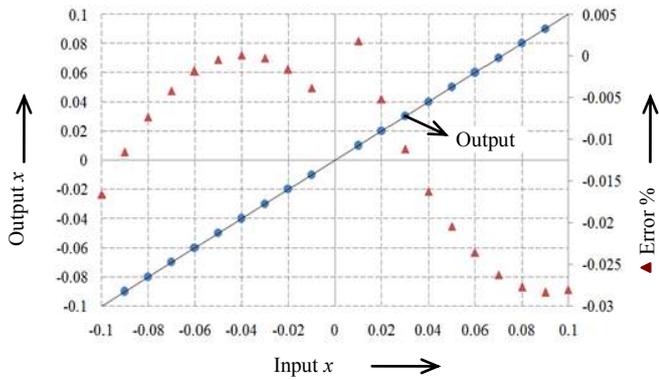
Fig. 4. Results of simulation studies

Fig. 6. Experimental setup to test the proposed DDC

switches S_1 and S_2 were realized using IC MAX 4602, possessing quad SPST switches having ON resistance of 2.5 Ω. To obtain the SPDT operation required for switches S_1 and S_2, each SPDT switch was realized by connecting two SPST switches in parallel. While the control of one of the parallel connected SPST switch was fed directly from the CLU, the control of the other switch was fed through a NOT gate (IC SN7404). The feedback capacitor of the integrator was selected to be polypropylene type of value 0.33 µF and a metal film resistor of value 100 kΩ served as R_I. IC LM311 was used as the comparator.

The Control and Logic Unit was implemented with an Arduino UNO board containing an ATMEGA 328 micro controller [16]. The Arduino board was interfaced to a personal computer (PC) utilizing the onboard USB interface. The PC not only served to cross compile and program the microcontroller, but also served as the output display. A suitable program, developed to implement the necessary logic illustrated in the flowchart of Fig. 3, is burnt into the microcontroller [17]. The program makes use of one of the timer-counters of the microcontroller for realizing the timing/counting operations outlined in Fig. 3. Using the internal clock of the microcontroller, the first integration period T_1 is set as 300 ms. The output N_o is obtained in terms of counts read from the internal counter-timer and the count values are displayed on the PC.
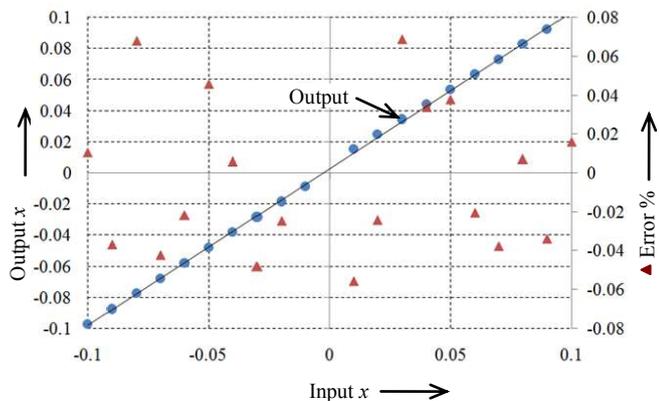
In order to obtain the performance characteristics of the proposed DSDDC under controlled input conditions, sensor elements R_1, R_2, R_3 and R_4, were realized using standard variable resistance boxes form Otto Wolff, Germany having a resolution of 1.0 Ω and an accuracy of ±0.01%. R_o for all the four resistors was selected to be 1.0 kΩ and the measurements were obtained by varying the physical quantity x in steps of 0.01 from -0.1 to +0.1 through zero. The results obtained from this emulation test of the prototype are shown in Fig. 5. The worst-case error observed from the emulation study was found to be < ±0.07 %

To establish the suitability of the proposed DSDDC for a practical application, the prototype unit was also tested using a load cell made of four resistive strain gauges connected in bridge form. The experimental setup utilized for conducting this test is shown in Fig. 6. The load-cell used is a standard aluminum single point, 290 Ω nominal value load cell of full scale 3.0 kg and sensitivity of 0.48 mΩ/kg. The feedback capacitance, C_I was chosen as 100 nF. The load cell was loaded in the 0 kg to 3 kg range in steps of 250 g. While it was possible to vary kx both in the positive and negative directions in the emulation study, kx varied only in the positive direction in the tests carried out with the load cell. The snapshot of integrator output, v_{oi} and comparator output, v_C for a typical kx value obtained from the prototype using the oscilloscope module of NI ELVIS II is shown in Fig. 7. The results obtained with the load cell, plotted in Fig. 8, illustrate that the worst case error is < ±0.05%.

Fig. 5. Experimental results obtained by emulating the sensor resistors R_1, R_2, R_3 and R_4 using standard resistance boxes
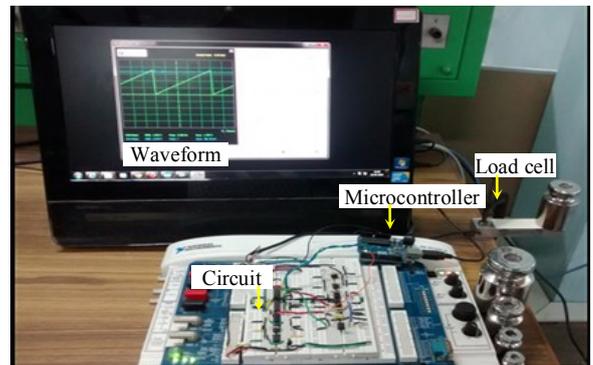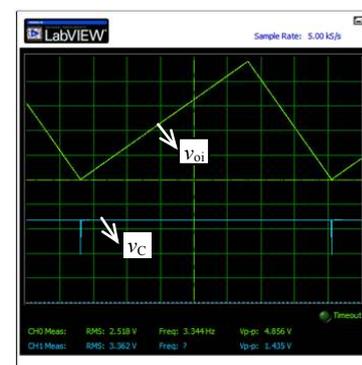

Fig. 7. Snapshot of integrator and comparator output waveforms observed from the prototype.
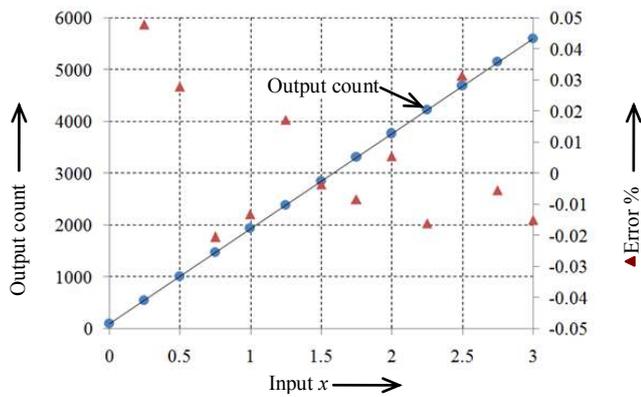
Fig. 8. Experimental results obtained with load cell

V. CONCLUSION

A dual slope type direct digital converter (DSDDC) that provides a digital output linearly proportional to the input quantity being sensed by bridge connected resistive sensing elements is presented. The Wheatstone bridge configuration of sensing elements becomes an integral part of a suitably augmented dual slope analog to digital converter. The dual slope digital converter in conjunction with a modified instrumentation amplifier enables conversion of the physical quantity being sensed by the resistive elements directly into digital form.

The suitability of the proposed scheme even for resistive sensing elements possessing very low sensitivity (10^{-3}) has been established with tests conducted on a load cell made of strain gauges possessing a gage factor of 2.5. Since the proposed DSDDC is of dual slope type, all the advantages of the dual slope principle such as good resolution, accuracy, tolerance to component variations and immunity from noise and interference are applicable to the proposed DSDDC. Results obtained from (i) simulation study, (ii) emulation study and (iii) practical experimentation using a strain gauge type load cell on a prototype DSDDC establish the efficacy of the proffered scheme.

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